

MEETING Minutes				Chapter Officers			
<b>Meeting Type:</b>	Technical Presentation			<b>Chairperson:</b>	Doug Parker	doug.parker@adtran.com	
<b>Subject:</b>	<b><i>ESD Susceptibility Scanning</i></b>			<b>Co-chairperson:</b>	Jeff Whitmire	jeff.whitmire@adtran.com	
<b>Date:</b>	21 May 2009			<b>Treasurer:</b>	Jim Stone	James.A.Stone@us.ul.com	
<b>Location:</b>	ADTRAN, 2 East Conference Center Room No. 273			<b>Secretary:</b>	Jack McFadden	jack.mcfadden@wyle.com	
<b>Champion:</b>	Doug Parker						
<b>Attendees:</b>							
<b>IEEE Members:</b>	<b>25</b>	<b>Guests:</b>	<b>16</b>	<b>Students:</b>	<b>4</b>	<b>Total</b>	<b>45</b>
<b>Minutes recorded by</b>   D. Parker							
<b>Meeting Agenda:</b>							
<ol style="list-style-type: none"> <li>1. Invitation/Social/Meal/Sign-In</li> <li>2. Recognition Of Meal Sponsor</li> <li>3. Chapter Business</li> <li>4. Technical Presentation</li> <li>5. Question/Answer Session</li> <li>6. Adjourn</li> </ol>							
<b>Meal Sponsor :</b>		Mr. Michael Hopkins			Amber Precision		
<b>Technical Presenter:</b>		Mr. Michael Hopkins			Amber Precision		
<b>Discussion</b>							
<b>Item 1;</b> The meeting was chaired by Doug Parker. He welcomed everyone and requested they sign-in.							
<b>Item 2;</b> The meal, <i>Barbeque Pork and Chicken Dinner</i> , was provided by Mr. Michael Hopkins from Amber Precision.							
<b>Item 3;</b> Chapter business was championed by Doug Parker. The information included chapter finances, upcoming events, sponsorship and volunteer opportunities for the meetings participates.							
<b>Item 4;</b>  Technical presentation, " <b><i>ESD Susceptibility Scanning</i></b> "  There is a disconnect in the EMC world between system manufacturers testing systems for upset and device manufacturers testing devices for failure. Some system level manufacturers are pushing device manufacturers to test semiconductor devices using system level compliance standards – specifically, IEC 61000-4-2 for ESD (Electrostatic Discharge). I'm sure the product manufacturers believe that if devices are qualified to IEC standard(s), finished products will likewise be qualified. Unfortunately, there is a fundamental difference between system level and device level testing; fortunately however, this difference can be bridged using susceptibility scanning.							
<b>Item 5;</b> Mr. Michael Hopkins answered questions from the attendees and made himself available after the meeting to discuss questions further.							
<b>Item 6;</b> Doug Parker presented the speaker with a small token of appreciation and adjourned the meeting at approximately 8:00 pm.							
<b>Action Item List</b>							
<b>Champion Name</b>	<b>Description</b>	<b>Initial Due Date</b>	<b>Status</b>	<b>Close Date</b>			

TBD = to be determined